SPIRE	Project Document	Ref	SPIRE-RAL-PRJ-0001079
		Issue	8.1
	Non-conformance Reports	Date	05 April 2005
	Status Report		

SPIRE

SUBJECT:	Non-Conformance Reports Status Report (CQM Open)					
PREPARED BY:	E A Clark					
DOCUMENT No:	SPIRE-RAL-PRJ-0001079					
Note This document is not signed as it contains information regarding the Open CQM NCR's only this information has been extracted from SPIRE-RAL-PRJ-0001079 issue 8.0						
APPROVED BY:	Name	Signature & Date				
Project Manager	K.J. King	Not applicable See SPIRE-RAL-PRJ-0001079v8.0				
Instrument Development Manager	E. Sawyer	Not applicable See SPIRE-RAL-PRJ-0001079v8.0				
Product Assurance Manager	Eric Clark	Not applicable See SPIRE-RAL-PRJ-0001079v8.0				

Distribution

CQM EIDP SPIRE-RAL-PRJ- 001898-Issue 3.0 incorporating Warm Electronics.



List of RAL Non-Conformances

PRODUCT ASSURANCE SPACE SCIENCE DEPARTMENT

Rutherford Appleton Laboratory

Spacecraft/Project: Herschel Originator: RAL/SSTD/PA

Instrument: SPIRE Model: Open CQM only Document No PIRE-RAL-PRJ-0001079 Issue: 8.1

Subsystems: Date: 05-Apr-05

NCR Serial No.	Level	Subsystem Assembly/ Part	Model	NCR Title	Issue Date	Disposition/Corrective Actions	References	Close Out Date
HR-SP-RAL-NCR- 87	Major	JFET's		One JFET Turned on one did not during 2nd cold test.		Spare JFETS sent to replace damaged JFETS and the da JFET REPLACED ON CQM Progression of NRB's held:SPIRE-RAL-MoM-002193, 002193v1, 002243, and 002243v1		
HR-SP-RAL-NCR- 91		FPU PCAL	CQM	Drive shorted to shield in FPU	04	USE as is for CQM, leave OPEN for PFM If, as assumed, this was always the case for the CQM it has no effect on the PCAL operation as the shield wire is not connected to chassis at any point in the system. We		
HR-SP-RAL-NCR- 92.2	Major	FPU/JFP/JFS		SPIRE EQM Electrical Interface Bench Test Anomalies	12-Jan-05	USE as is for CQM, leave OPEN for PFM NRB ref SPIRE-RAL-MoM-002304		
HR-SP-RAL-NCR- 96	Major	FPU	PFM CQM	L1 electrical short		The cause of the short to be investigated. Ref NRB SPIRE-RAL-MoM-002247 (v1 to v3) Agreed to use as is. Leave NCR open until isolation test plan is established for PFM		
HR-SP-RAL-NCR- 105	,	MCU CQM1	CQM	Simultaneous generation of BSM and SMEC frames leads to Frame ID error reports	03-Feb-05	TBD No effect on EQM Testing (MCU not used).		

END OF LIST